

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/574,278 WADA ET AL.	
		Examiner	Art Unit Mark L. Berch	1624 Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0162277	08-2004	Shimbayashi et al.	514/192
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lin et al., Huaxue Gongye Yu Gongcheng (Tianjin, China) (2002), 19(3), 219-224, 273
	V	Partial translation of Lin et al., Huaxue Gongye Yu Gongcheng (Tianjin, China) (2002), 19(3), 219-224, 273
	W	Chen et al., Shanxi Daxue Xuebao, Ziran Kexueban (2001), 24(4), 329-330
	X	Partial translation of Chen et al., Shanxi Daxue Xuebao, Ziran Kexueban (2001), 24(4), 329-330

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/574,278 WADA ET AL.	
		Examiner	Art Unit	Page 2 of 3 Mark L. Berch 1624

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bai et al., Jingxi Huagong (2001), 18(11), 634-637
	V	Partial translation of Bai et al., Jingxi Huagong (2001), 18(11), 634-637
	W	Deng et al., Zhongguo Yaowu Huaxue Zazhi (2001), 11(2), 93-95
	X	Partial translation of Deng et al., Zhongguo Yaowu Huaxue Zazhi (2001), 11(2), 93-95

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/574,278 WADA ET AL.	
		Examiner	Art Unit	Page 3 of 3 Mark L. Berch 1624

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Liu et al., Taiyuan Ligong Daxue Xuebao (2002), 33(6), 663-665
	V	Partial translation of Liu et al., Taiyuan Ligong Daxue Xuebao (2002), 33(6), 663-665
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.